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	Application No.	Applicant(s)	
Notice of Allowability		HUANG ET AL.	
	10/721,126 Examiner	Art Unit	
		2010	
	Stephen W. Smoot	2813	
The MAILING DATE of this communication appeal All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI	(OR REMAINS) CLOSED in this ap or other appropriate communication IGHTS. This application is subject t	plication. If not included now will be mailed in due course. THIS	
1. X This communication is responsive to applicant's amendme	nt filed on 29 November 2005.		
2. 🔀 The allowed claim(s) is/are <u>23-41</u> .			
3. ☐ Acknowledgment is made of a claim for foreign priority ur a) ☐ All b) ☐ Some* c) ☐ None of the:			
1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No.			
2. Certified copies of the priority documents have been received in Application No			
3. Copies of the certified copies of the priority documents have been received in this national stage application from the			
International Bureau (PCT Rule 17.2(a)).			
* Certified copies not received:			
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		complying with the requirements	
4. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give			
5. CORRECTED DRAWINGS (as "replacement sheets") must be submitted.			
(a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached			
1) hereto or 2) to Paper No./Mail Date			
(b) ☐ including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment or in the C	Office action of	
Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t			
 DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT 	sit of BIOLOGICAL MATERIAL I FOR THE DEPOSIT OF BIOLOGIC	must be submitted. Note the AL MATERIAL.	
Attachment(s) 1. ☐ Notice of References Cited (PTO-892)	5. Notice of Informal F	Patent Application (PTO-152)	
2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. ☐ Interview Summary		
	Paper No./Mail Da	te .	
 Information Disclosure Statements (PTO-1449 or PTO/SB/C Paper No./Mail Date 	08), 7. ☐ Examiner's Amenda	ment/Comment	
4. Examiner's Comment Regarding Requirement for Deposit	8. 🛛 Examiner's Stateme	ent of Reasons for Allowance	
of Biological Material	9.	9. Other	
Hothen . W.	1. Imost	Stephen W. Smoot Patent Examiner Art Unit 2813	

Application/Control Number: 10/721,126 Page 2

Art Unit: 2813

DETAILED ACTION

This Office action is in response to applicant's amendment filed on 29 November 2005.

Drawings

1. Replacement drawing sheets corresponding to Figs. 1, 2 and to Figs. 27, 28 were received on 29 November 2005. These drawings are acceptable.

Allowable Subject Matter

- 2. Claims 23-41 are allowed.
- 3. The following is an examiner's statement of reasons for allowance:
 - Claims 23-27 are allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a method of forming a via and a trench through dielectric material that avoids effects due to misalignment that includes the steps of forming a mask layer over the dielectric material,

Application/Control Number: 10/721,126

Art Unit: 2813

forming a via in the mask layer to a first predetermined depth by etching, and forming a trench in the mask layer to a second predetermined depth by etching, wherein the mask layer comprises at least two pairs of mask films, wherein the second predetermined depth is less than the first predetermined depth, and wherein the dielectric material is not exposed until after the step of removing any material from the via that may remain as a consequence of misalignment between the trench and the via;

Page 3

- Claims 28-39 are allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a method of forming a via and a trench through dielectric material that avoids effects due to misalignment that includes forming in sequence first, second, third, and fourth mask films over the dielectric material, forming a via to a first predetermined depth by etching the second, third, and fourth mask films, and forming a trench to a second predetermined depth by etching at least the fourth mask film, wherein the second predetermined depth is less than the first predetermined depth, and wherein the dielectric material is not exposed until after the step of removing any material from the via that may remain as a consequence of misalignment between the trench and the via; and
- Claims 40-41 are allowed because the prior art of record does not teach or suggest, in combination with the other claim limitations, a semiconductor device having a dielectric material deposited over an underlying interconnect layer that includes first, second, third, and fourth mask films formed in sequence over the

dielectric material, a via formed to a first predetermined depth by etching at least some of the mask films, and a trench formed to a second predetermined depth by etching at least some of the mask films, wherein the first and third mask films have substantially identical etch properties and the second and fourth mask films have substantially identical etch properties, wherein the second predetermined depth is less than the first predetermined depth, and wherein any material remaining in the via as a consequence of misalignment can be removed prior to exposing the dielectric material.

Page 4

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

4. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Stephen W. Smoot whose telephone number is 571-272-1698. The examiner can normally be reached on M-F (8:00 am to 4:30 pm).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl Whitehead, Jr. can be reached on 571-272-1702. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/721,126 Page 5

Art Unit: 2813

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

SWS